

FDS3890

80V N-Channel Dual PowerTrench® MOSFET

General Description

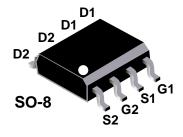
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

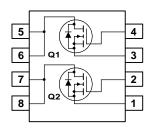
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $R_{\rm DS(ON)}$ specifications. The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

Features

4.7 A, 80 V. $R_{DS(ON)} = 44 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 50 \text{ m}\Omega @ V_{GS} = 6 \text{ V}$

- · Fast switching speed
- High performance trench technology for extremely low $R_{\mbox{\scriptsize DS}(\mbox{\scriptsize ON})}$
- · High power and current handling capability





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V _{DSS}	Drain-Source Voltage		80	V	
V _{GSS}	Gate-Source Voltage		± 20	V	
I _D	Drain Current - Continuous	(Note 1a)	4.7	А	
	– Pulsed		20		
P _D	Power Dissipation for Dual Operation		2	W	
	Power Dissipation for Single Operation	(Note 1a)	1.6		
		(Note 1b)	1.0		
		(Note 1c)	0.9		
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +175	°C	

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
R _{θJC}	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS3890	FDS3890	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	ource Avalanche Ratings (Note	2)	1			ı
W _{DSS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 40 \text{ V}, I_D = 4.7 \text{ A}$			175	mJ
I _{AR}	Maximum Drain-Source Avalanche Current				4.7	Α
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	80			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		86		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 64 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}$ $V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2	2.3	4	V
$\Delta V_{GS(th)}$ $\Delta T_{,J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to 25°C		-6		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V}, \qquad I_D = 4.7 \text{ A}$ $V_{GS} = 6.0 \text{ V}, \qquad I_D = 4.4 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 4.7 \text{ A}, T_J = 125^{\circ}\text{C}$		34 37 60	44 50 82	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	20			Α
g _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 4.7 \text{ A}$		24		S
Dvnamio	Characteristics			•	•	•
C _{iss}	Input Capacitance	$V_{DS} = 40 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		1180		pF
Coss	Output Capacitance	f = 1.0 MHz		171		pF
C _{rss}	Reverse Transfer Capacitance			50		pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 40 \text{ V}, \qquad I_D = 1 \text{ A},$		11	20	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		8	16	ns
t _{d(off)}	Turn-Off Delay Time	7		26	50	ns
t _f	Turn-Off Fall Time			12	25	ns
Q_g	Total Gate Charge	$V_{DS} = 40 \text{ V}, \qquad I_{D} = 4.7 \text{ A},$		25	35	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		4.5		nC
Q_{gd}	Gate-Drain Charge			5.8		nC
Drain-So	ource Diode Characteristics a	and Maximum Ratings				
Is	Maximum Continuous Drain–Source				1.3	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 1.3 A (Note 2)		0.74	1.2	V

Notes

1. R_{8JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{8JC} is guaranteed by design while R_{8CA} is determined by the user's board design.



a) 78°C/W when mounted on a 1in² pad of 2 oz copper



b) 125°C/W when mounted on a .04 in² pad of 2 oz copper





c) 135°C/W when mounted on a minimum pad.

^{2.} Pulse Test: Pulse Width < $300\mu s$, Duty Cycle < 2.0%

Typical Characteristics

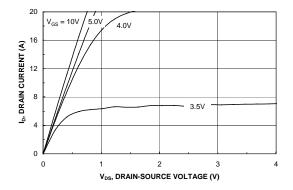


Figure 1. On-Region Characteristics.

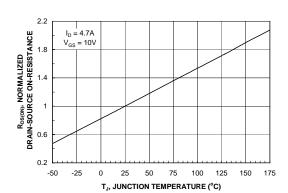


Figure 3. On-Resistance Variation with Temperature.

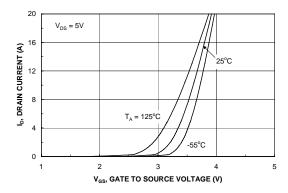


Figure 5. Transfer Characteristics.

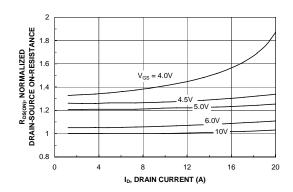


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

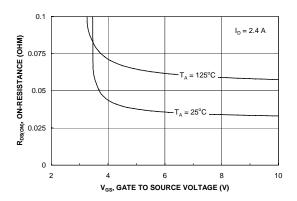


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

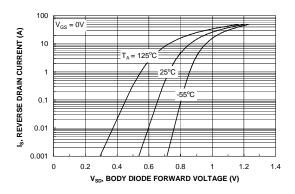
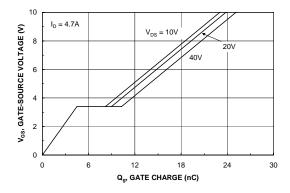


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



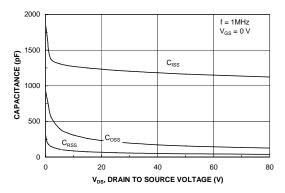
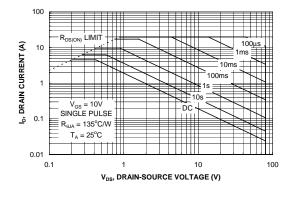


Figure 7. Gate Charge Characteristics.





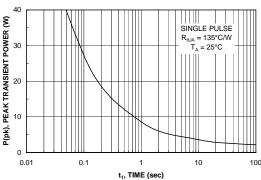


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

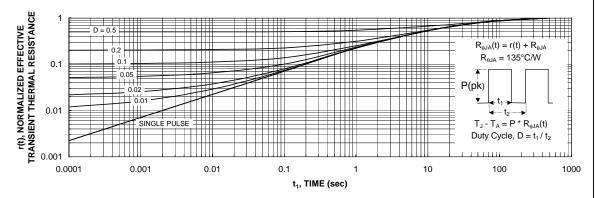


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c.

Transient thermal response will change depending on the circuit board design.

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